		Complete If Known			
O PE WIFORMATION DISCLOSU	ЛE	Application Number	10/825,795		
OTTATION		Filing Date	April 13, 2004		
/ % \ &\		First Named Inventor	Jun Li		
NAY 0 8 2006) PTO-1449		Art Unit	3753		
		Examiner Name	Teresa J. Walberg		
Sheet I of	7	Attorney Docket Number	ARC-15173-1		

			U.S. PATEN	T DOCUMENTS						
Examiner Initials	Cite No.	Document Number Number - Kind Code ¹	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	С	lass	Sub	class	Filing Appro	
TW		20020130407A1	09-19-2002	Dahl et al.						
TW		20020145194A1	10-10-2002	O'Conner et al.						
TW		20020163079A1	11-07-2002	Awano						
TW		2002090501A1	7-11-2002	Tobita						
TW		2002100581A1	8-1-2002	Knowles, et al.	1					
TW		2002130407A1	9-19-2002	Dahl et al.						
ľW		20030111333A1	06-03-2003	Montgomery, et al.	1	T				
TW		20030117770A1	06-26-2003	Montgomery, et al.	İ					
TW		20030231471A1	12-18-2003	De Lorenzo et al.						
TW		20040013598A1	01-22-2004	McElrath et al.	1		<u> </u>		i	
TW		2004005736A1	1-8-2004	Searls et al.	1					
TW		20040218362	11-4-2004	Amaro et al.		<u> </u>	<u> </u>			
TW		20040261978A1	12-30-2004	Zhan et al.						
TW		20040261987	12-30-2004	Zhang et al.						
TW		20040265489A1	12-30-2004	Dubin						
TW		20040266063A1	12-30-2004	Montgomery et al.	1					
TW		20040266065A1	12-30-2004	Zhang et al.						
		-	FOREIGN PAT	ENT DOCUMENTS					-	
Examiner	Cite	Foreign Patent Document	Publication Date	Name of Patentee or			Transla		lation	
Initials	No.	Country Code ² - Number ³ - Kind Code ⁴ (if known)	MM-DD-YYYY	Applicant of Cited Document	С	lass	Sub	class	Yes	No
				·						
					<u> </u>					
				ITERATURE DOCUMENT						
Examiner Initials	Cite No.			ERS), title of the article (when appage(s), volume-issue number(s), pu						
1111111111	INU.	Journal, Scrial, Symposium	, caralog, erc. j, uate, pa	65-(3), volume-issue number(s), pt	ואוואוועו	, city a	ט וטשום	Juliu y V	There pub	issicu

Examiner	/Teresa Walberg/	Date	06/20/2006
Signature		Considered	

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

See Kind Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. Applicant is to place a check mark here if English language Translation is attached. Burden Hour Statement: This form is estimated to take 2.0 hours to complete. Time will vary depending upon the needs of the individual case. Any comments on the amount of time you are required to complete this form should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS

ADDRESS. SEND TO: Assistant Commissioner for Patents B.O. Pay 1450. Algorithm VA. 22212 1450.

				Complete If Known			
INFO	FORMATION DISCLOSURE			Application Number	10/825,795		
CITATION				Filing Date	April 13, 2004		
	-	· -		First Named Inventor	Jun Li		
	PT	O-1449		Art Unit	3753		
				Examiner Name	Teresa J. Walberg		
Sheet	2	of	7	Attorney Docket Number	ARC-15173-1		

			U.S. PATENT	OCUMENTS				
Examiner	Cite	Document Number	Publication Date	Name of Patentee or				-
Initials	No.	Number - Kind Code	MM-DD-YYYY	Applicant of Cited Document	Class	Subclass	Filing I	
TW		20040053053A1	3-18-2004	Jiang et al.		1		
TW		20040101468A1	5-27-2004	Liu et al.				
TW	•	20040146560A1	7-29-2004	Whiteford, et al.				
TW		20040150100A1	8-5-2004	Dubin, et al.				
TW		20040182600A1	9-23-2004	Kawabata, et al.				
TW		20040184241A1	9-23-2004	De Lorenzo, et al.				
TW		20040191158A1	9-30-2004	Liu, et al.				
TW		20040218362	11-04-2004	Amaro, et al.				
TW		20040261987	12-30-2004	Zhang, et al.				
TW		20050006754A1	01-13-2005	Arik et al.				
TW		20050037204A1	02-17-2005	Oslander et al.		1 .		
TW		20050061496A1	3-24-2005	Matabayas				
TW		20050067693A1	3-31-2005	Nihei, et al.				
TW		20050092464A1	5-5-2005	Leu, et al.				
TW		20050116336A1	6-2-2005	Chopra, et al		 		
TW		20050136248A1	6-23-2005	Leu, et al.				
TW	-	20050139642A1	6-30-2005	Koning, et al				
			FOREIGN PATER		<u> </u>		L	
		Foreign Patent Document	Publication	Name of Patentee or			Trans	lation
Examiner Initials	Cite No.	Country Code ² - Number ³ - Kind Code ⁴ (if known)	Date MM-DD-YYY Y	Applicant of Cited Document	Class	Subclass	Yes	No
					ļ	 	•	
					-			
					<u> </u>	-		
		ОТН	ER NON PATENT	LITERATURE DOCUME	NTS	_L		
Examiner	Cite	Include name of the author (in (CAPITAL LETTERS), title of the article (when appropr	iate), title of th	e item (book, mag	azine,	
Initials	No.	journal, serial, symposium, cata	alog, etc.), date, page(s),	, volume-issue number(s), publish	er, city and/or	country where pu	blished	

Examiner	/Teresa Walberg/	Date	06/20/2006
Signature	,, ·	Considered	

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

See Kind Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. Applicant is to place a check mark here if English language Translation is attached.

				Complete	If Known
INF	ORMATIC	ON DISCLOS	SURE	Application Number	10/825,795
CITATION				Filing Date	April 13, 2004
	-			First Named Inventor	Jun Li
	PT	O-1449		Art Unit	3753
				Examiner Name	Teresa J. Walberg
Sheet	3	of	7	Attorney Docket Number	ARC-15173-1

			U.S. PATENT I	DOCUMENTS				
Examiner	Cite	Document Number	Publication Date	Name of Patentee or				
Initials	No.	Number - Kind Code	MM-DD-YYYY	Applicant of Cited Document	Class	Class Subclass		Date opriate
TW		20050139991A1	6-30-2005	White, et al.				
TW		20050150887A1	7-14-2005	Taya, et al.				
TW		20050167647A1	8-4-2005	Huang et al.				•
TW		20050224220A1	10-13-2005	Li, et al.				
TW		20050238810A1	10-27-2005	Scaringe, et al.				
TW		20050260412A1	11-24-2005	Gardner				
TW		20050269726A1	12-8-2005	Matabayas, JR.				
TW		5,818,700	10/6/1998	Purinton; Donald L.				
TW		5,837,081	11/17/1998	Ting, et al.				
TW		5,926,370	07/20/1999	Cromwell				
TW :		5,965,267	10/12/1999	Nolan, et al.				
TW		6,156,256	12/5/2000	Kennel				
TW		6,231,744 B1	05-15-2001	Ying et al.				
TV	7	6,340,822	1/22/2002	Brown, et al.				
TW		6,359,288 B1	03-19-2002	Ying et al.				
TW		6,383,923	5/7/2002	Brown, et al				
TW		6,407,922B1	06-18-2002	Eckblad et al.				
		FC	DREIGN PATENT	DOCUMENTS	•			
Examiner	Cite	Foreign Patent Document	Publication Date	Name of Patentee or			Translation	
Initials	No.	Country Code ² - Number ³ - Kind Code ⁴ (if known)	MM-DD-YYYY	Applicant of Cited Document	Class	Subclass	Yes	No
								
		OTHE	D NON DATENT	LITERATURE DOCUMENTS			,	
Examiner	Cite			s), title of the article (when appropri		f the item (boo	k magazir	nc
Initials	No.			e(s), volume-issue number(s), publis				

Examiner /Tere	sa Walberg/	Date	06/20/2006
Signature / Tele	sa walberg/	Considered	

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in

conformance and not considered. Include copy of this form with next communication to applicant.

See Kind Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. Applicant is to place a check mark here if English language Translation is attached.

				Complete	If Known			
INFORMATION DISCLOSURE			OSURE	Application Number	10/825,795			
	CITATION			Filing Date	April 13, 2004			
				First Named Inventor	Jun Li			
•	PTO	O-1449		Art Unit	3753			
				Examiner Name	Teresa J. Walberg			
Sheet	4	of	7	Attorney Docket Number	ARC-15173-1			

			U.S. PATENT	DOCUMENTS						
Examiner	Cite	Document Number	Publication Date	Name of Patentee or						
Initials	No.	Number - Kind Code	MM-DD-YYYY	Applicant of Cited Document	C	lass	Sub	Subclass Filing Dat Appropria		
TW		6,432,740 B1	08-13-2002	Chen			TT			
TW		6,452,274	09/17/2002	Hasegawa et al.						
TW		6,504,292	1/7/2003	Choi, et al.						
TW		6,713,151	3/30/2004	Dean, et al						
TW		6,800,886	10/5/2004	Awano	\neg					
TW		6,855,376	2/15/2005	Hwangg et al.						
TW		6,856,016 B2	02-15-2005	Searls et al.						
TW		6,864,571 B2	03-08-2005	Arik et al.			1 1			
TW		6,891,724	5/10/2005	De Lorenzo, et al.			1 1			
TW		6,921,462	7/26/2005	Montgomery, et al.			\Box			
TW		6,924,335	8/2/2005	Fan, et al.		-	1 1			
TW		6,962,823	11/8/2005	Empedocles, et al.			1			
TW		6,989,325	1/24/2006	Uang, et al.		-	\Box			-
TW		6,965,513B2	11-15-2005	Montgomery et al.	_		† †			
		,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	11.12.20				†			
							1			
			·							
. •		1	FOREIGN PATEN	T DOCUMENTS						
Examin	Cite	Foreign Patent Document	Publication Date	Name of Patentee or	T		Subclas		Translation	
er Initials	No.	Country Code ² - Number ³ - Kind Code ⁴ (if known)	MM-DD-YYYY	Applicant of Cited Document	С	lass		S	Yes	No
TW		WO 03/054958A1	07-03-2003	Intel Corporation				٠		
TW		EP 1329953A1	08-03-2003	Intel Corporation						
TW		WO 03/072679A1	09-04-2003	Carbon Nanotechnologies, Inc.						
TW		WO 03/107419A1	12-24-2003	Intel Corporation						
		OTI	IER NON PATEN	T LITERATURE DOCUMEN	ΓS		-			
Examiner	Cite			, title of the article (when appropriate),						
Initials	No.			volume-issue number(s), publisher, cit						
TW ·				eneous ICs: A Technology Il Propagation on Intercont						3-16,

Examiner	/Teresa Walberg/	Date	06/20/2006
Signature	/ reresu warserg/	Considered	00/20/2000

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ See Kind Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ² Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ³ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁴ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁵ Applicant is to place a check mark here if English language Translation is attached.

				Complete	! If Known
I)	VFORMATIO	ON DISCLO	SURE	Application Number	10/825,795
CITATION				Filing Date	April 13, 2004
				First Named Inventor	Jun Li
	PT	O-1449		Art Unit	3753
				Examiner Name	Teresa J. Walberg
Sheet	5	of	7	Attorney Docket Number	ARC-15173-1

	·
TW	Berber, et al., Unusually High Thermal Conductivity of Carbon Nanotubes, Physical Review Letters, 05/15/2000, 4613-4616, Vol. 84, No 20.
TW	Cassell, Alan, "Directed Growth of Free-Standing Single-Walled Carbon Nanotubes", J Am Chemical Society, 1999, 121, pgs. 7975-7976.
TW	Chiang, Ting-Yen, "A New Analytical Thermal Model for Multilevel ULSI Interconnects Incorporating Via Effect", Center for Integrated Systems, Stanford University (no date given).
TW	Chiang, Ting-Yen, et al., "Effect of Via Separation and Low-k Dielectric Materials on the Thermal Characteristics of Cu Interconnects", <i>IEDM 2000</i> (no date).
TW	Chuang, Helen F., et al., "Inprovement of Thermal Contact Resistance by Carbon Nanotubes and Nanofibers," Journal of Nanoscience and Nanotechnology (2004), Vol. 4, No. 8, pgs. 964-967, American Scientific Publishers.
TW	Cui, Yi, et al., "Doping and Electrical Transport in Silicon Nanowires", Journal of Physical Chemistry. Vol. 104, No. 22, June 8, 2000, pgs. 5213-5216.
TW	de Pablo, P.J., "A simple, reliable technique for making electrical contact to multiwalled carbon nanotubes", <i>Applied Physics Letters</i> , Vol;. 74, No. 2, January 11, 1999, pgs. 323-325.
TW	Delzeit, Lance, et al., "Growth of carbon nanotubes by thermal and plasma chemical vapour deposition processes and applications in microscopy", <i>Nanotechnology</i> , Vol. 13, May 23, 2002, pgs. 280-284.
TW	Delzeit, Lance, et al., "Growth of multiwall carbon nanotubes in an inductively coupled plasma reactor", Journal of Applied Physics, Vol, 91, No. 9, May 1, 2002, pgs. 6027-6033.
TW .	Goodson, K.E., et al., "Improved Heat Sinking for Laser-Diode Arrays Using Microchannels in CVD Diamond", <i>IEE Transactions on Components, Packaging, and Manufacturing Technology</i> , Part B, Advanced Packaging, Vol. 20, Issue 1, February 1997. pgs. 104-109.
TW	Hone, J., et al., "Thermoelectric Power of Single-Walled Carbon Nanotubes", <i>Physical Review Letters</i> , Vol, 80, No. 5, Febbuary 2, 1998, pgs. 1042-1045.
TW	Huang, Z.P., et al. "Growth of highly oriented carbon nanotubes by plasma-enhanced hot filament chemical vapor deposition", <i>Applied Physics Letters</i> , Vol, 73, No. 26, December 28, 1998, pgs. 3845-3847.
TW	International Semiconductor Road Map (ITRS-2001), Section on Interconnect, http://public/itrs.net/files/2001ITRS/interconnect.pdf.
TW	Kim, Mun Ja, et al., "Growth characteristics of carbon nanotubes via aluminum nanopore template on Si substrate using PECVD", Elsevier Thin Solid Films, Vol, 425, 2003, pgs. 312-317.
TW	Kong, Jing, et al., "Systhesis of individual single-walled carbon nanotubes on patterned silicon wafers", <i>Nature</i> , Vol, 395, Oct. 29, 1998, pgs. 878-881.

				_
Examiner	/Teresa Walberg/	Date	06/20/2006	
Signature	•	Considered	1 00,000	

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ See Kind Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ² Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ³ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁴ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁵ Applicant is to place a check mark here if English language Translation is attached.

				Complete	If Known
INF(ORMATIC	ON DISCLO	SURE	Application Number	10/825,795
CITATION . PTO-1449				Filing Date	April 13, 2004
				First Named Inventor	Jun Li
				Art Unit	3753
		Examiner Name	Teresa J. Walberg		
Sheet	6	of	7	Attorney Docket Number	ARC-15173-1

TW	Kurabayashi, K, et al., "Precision Measurement and Mapping of Die-Attach Thermal Resistance",			
	IEEE Transactions on Components, Packaging, and Manufacturing			
	Technology, Part A: Advanced Packaging, Vol. 21, Issue 3, September 1998. pgs. 506-514			
TW	Li, Jun, et al., "Electronic properties of multiwalled carbon nanotubes in an embedded vertical			
	агтау", Applied Physics Letters, Vol. 81, No. 5, July 29, 2002, pgs. 910-912.			
TW	Li, Jun, et al., "Bottom Up Approach for Carbon Nanotube Interconnects, Applied Phys. Letters,			
	4/18/2003, 2491-2493, Vol 82, No. 15, American Institute of Physics			
TW	Liu, Jie, et al., "Controlled deposition of individual single-walled carbon nanotubes on chemically			
functionalized templates", Chemical Physics Letters, 303, April 2, 1999, pgs. 125-129.				
TW McEuen, Paul L., et al., "Single-Walled Carbon Nanotube Electronics", IEEE Transac				
	Nanotechnology, Vol, 1, No. 1, March 2002, pgs. 78-85.			
TW	Meyyappan, M., et al., "Carbon nanotube growth by PECVD: a review", Plasma Sources Science			
	and Technology, Vol. 12, April 2, 2003, pgs. 205-216.			
TW	Ren, Z.F., et al., "Synthesis of Large Arrays of Well-Aligned Carbon Nanotubes on Glass", Science,			
	Vol. 282, November 6, 1998, pgs. 1105-1107.			
TW .	Shi, Li., "A Microdevice for Measuring Thermophysical Properties of Nanowires and Nanotubes",			
-" 1	2001 ASME International Mechanical Engineering Congress and Exposition, November 11-16,			
	2001, pgs. 359-362.			
TW	Shi, Li., "Scanning thermal microscopy of carbon nanotubes using batch-fabricated probes", Applied			
	Physics Letters Vol. 77, No. 26, December 25, 2000, pgs. 4295-4297.			
TW	Stevens, R., "Improved fabrication approach for carbon nanotube probe devices", Applied Physics			
	Letters, Vol, 77, No. 21, November 20, 2000, pgs. 3453-3455.			
TW	Sun, X, et al., "Theoretical modeling of thermoelectricity in Bi nanowires", Applied Physics Letters,			
	Vol. 74, No. 26, June 28, 1999, pgs. 4005-4007.			
TW	Tu et al., Growth of Aligned Carbon Nanotubes with Controlled Site Density, Applied Phys. Letters,			
	05/27/2002, 4018-4020, Vol. 80, No 21, American Institute of Physics.			
TW	Viswanath, Ram, et al., "Thermal Performance Challenges from Silicon to Systems," Intel			
	Technology Journal Q3 Microprocessor Packaging, Vol. 4, Issue 3, August 2000.			
TW	Yakobson, Boris I., et al., "Fullerene Nanotubes: C _{1,000,000} and Beyond", American Scientist online,			
	http://www.americanscientist.org/template/AssetDetail/assetid/2870?fulltext=true&print=yes.			
TW	Zhang, Wei De, et al., "Synthesis of vertically aligned carbon nanotubes films on silicon wafers by			
	pyrolysis of ethylenediamine", Elsevier, Thin Solid Films, 422, 2002, pgs. 120-125.			
TW	Zhang, Yuegang, et al., "Electric-field-directed growth of aligned single-walled carbon nanotubes",			
-:-	Applied Physics Letters. Vol. 79, No. 19, November 5, 2001, pgs. 3155-3157.			

Examiner Signature	/Teresa Walberg/	Date Considered	06/20/2006

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ See Kind Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ² Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ³ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁴ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁵ Applicant is to place a check mark here if English language Translation is attached.

, , ,	_			Complete	If Known
Γ.	NFORMATIO	ON DISCL	OSURE .	Application Number	10/825,795
	CIT	ATION		Filing Date	April 13, 2004
				First Named Inventor	Jun Li
	PT	O-1449		Art Unit	3753
				Examiner Name	Teresa J. Walberg
Shee	7	of	7	Attorney Docket Number	ARC-15173-1

TW	Zhou, P., et al., "Thermomechanical Diagnostics of FLIP-CHIP/BGA Structures Using Phase-Shifting Electronic Speckle Pattern Interferometry", <i>EEP, Advances in Electronic Packaging</i> , Vol. 26-2, ASME, 1999, pgs. 1875-1880.						
	·						
	· · · · · · · · · · · · · · · · · · ·						

Examiner	/Teresa Walberg/	Date	06/20/2006
Signature	•	Considered	00/20/2000

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in

conformance and not considered. Include copy of this form with next communication to applicant.

See Kind Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. 4 Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. S Applicant is to place a check mark here if English language Translation is attached.

				Complete	e If Known
INF	ORMATIO	ON DISCL	OSURE	Application Number	10/825,795
	CIT	ATION		Filing Date	April 13, 2004
	011			First Named Inventor	Jun Li
	PΊ	ro-1449		Art Unit	3753
				Examiner Name	Teresa J. Walberg
Sheet	1	of	1	Attorney Docket Number	ARC-15173-1

•			U.S. PATENT	DOCUMENTS				
Examiner	Cite	Document Number	Publication Date	Name of Patentee or				
Initials	No.	Number - Kind Code	MM-DD-YYYY	Applicant of Cited Document	Class	Subclass	Filing Dr	
					·	<u> </u>		
						ļ		
								
						 		<u> </u>
						 		
						 	 	
						 		
						 		
						 	 	
						 		
						<u> </u>	· · · · · · · · · · · · · · · · · · ·	
		1	FOREIGN PATEN	T DOCUMENTS		<u> </u>		
xaminer	Cite	Foreign Patent Document	Publication Date	Name of Patentes or	,	T	Trans	lation
Initials	No.	Country Code ² - Number ³ - Kind Code ⁴ (if known)	MM-DD-YYYY	Applicant of Cited Document	Class	Subclass	Ycs	No
								
						<u> </u>		
				LITERATURE DOCUMEN				
Examiner Initials	Cite No.			title of the article (when appropriate), volume-issue number(s), publisher, cir				
TW	110.			l Nanowires on Suspended				
-''		Nanotubes", Appl. Phy			Singice	maneu Co	AI OUII	

Examiner	/Teresa Walberg/	Date	06/20/2006
Signature		Considered	

See Kind Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. Applicant is to place a check mark here if English language Translation is attached.

Burden Hour Statement: This form is estimated to take 2.0 hours to complete. Time will vary depending upon the needs of the individual case. Any comments on the amount of time you are required to complete this form should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Assistant Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.